

REMARKS

Please enter the above amendments prior to examination on the merits. If there are any question, please contact the undersigned at 408/453-9200.

EXPRESS MAIL LABEL NO:

EL-710-207-159 US

Respectfully submitted,



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754024 v1

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## Appendix A

The following is a marked up version of the amended paragraph beginning at page 1, line 18.

This application is a continuation of U.S. Patent Application Serial No. 08/954,765, filed October 20, 1997. In addition, this [This] application is related to and incorporates by reference herein in its entirety the concurrently filed, commonly owned U.S. Patent Application, Serial Number \_\_\_\_\_ [Attorney Docket Number M-5302 US] filed by Tai An Ly, et al., and entitled "A Method for Automatically Generating Checkers for Finding Functional Defects in a Description of a Circuit".

0064066-06404  
101050-50067360

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